

Notice of References Cited	Application/Control No. 09/995,696	Applicant(s)/Patent Under Reexamination WAKABAYASHI, TAKEFUMI	
	Examiner Sargon N. Nano	Art Unit 2157	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,631,407	10-2003	Mukaiyama et al.	709/223
	B	US-6,259,538	07-2001	Amit et al.	358/442
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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